

<IGBT Modules>

### CM400DY-13T

**HIGH POWER SWITCHING USE INSULATED TYPE** 



dual switch (half-bridge)

Collector current Ic ...... 4 0 0 A Collector-emitter voltage V<sub>CES</sub> ..... 6 5 0 V 1 7 5 °C Maximum junction temperature T<sub>vjmax</sub> .......

- •Flat base type
- Copper base plate (Nickel-plating)
- •Tin-plating signal terminals
- •RoHS Directive compliant
- •UL Recognized under UL1557, File No.E323585

#### **APPLICATION**

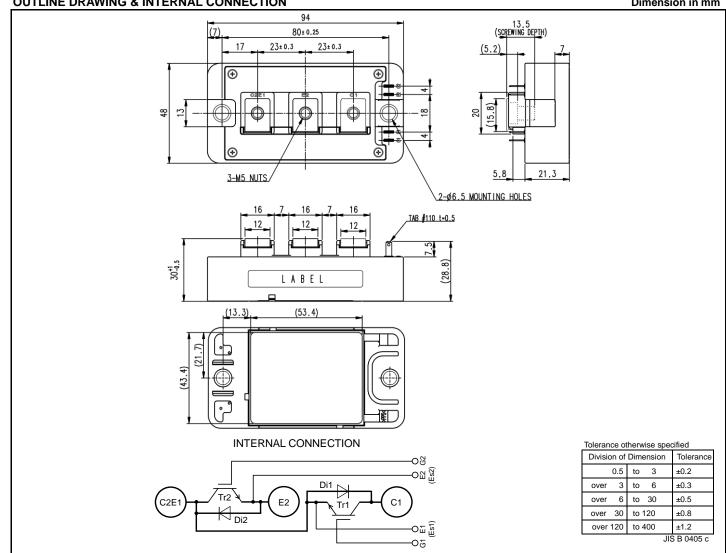
AC Motor Control, Motion/Servo Control, Power supply, etc.

**OPTION** (Below options are available.)

- ●PC-TIM (Phase Change Thermal Interface Material) pre-apply
- Vcesat selection for parallel connection

### **OUTLINE DRAWING & INTERNAL CONNECTION**

Dimension in mm



1

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### MAXIMUM RATINGS ( $T_{vj}$ =25 °C, unless otherwise specified)

Symbol	Item	Conditions	Rating	Unit	
V <sub>CES</sub>	Collector-emitter voltage	G-E short-circuited	650	V	
$V_{GES}$	Gate-emitter voltage	C-E short-circuited	± 20	V	
Ic	Collector current	DC, T <sub>C</sub> =125 °C (Note2, 4)	400	^	
I <sub>CRM</sub>	Collector current	Pulse, Repetitive (Note3)	800	Α	
P <sub>tot</sub>	Total power dissipation	T <sub>C</sub> =25 °C (Note2, 4)	2830	W	
I <sub>E</sub> (Note1)	Emitter current	DC (Note2)		^	
I <sub>ERM</sub> (Note1)	Emilier current	Pulse, Repetitive (Note3)	800	Α	
V <sub>isol</sub>	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	4000	V	
$T_{vjmax}$	Maximum junction temperature	Instantaneous event (overload)	175	°C	
T <sub>Cmax</sub>	Maximum case temperature			7	
T <sub>vjop</sub>	Operating junction temperature	Continuous operation (under switching)	-40 ~ +150	°C	
T <sub>stg</sub>	Storage temperature	-	-40 ~ +125		

### ELECTRICAL CHARACTERISTICS (Tvj=25 °C, unless otherwise specified)

Symbol	ltom	Conditions		Limits			Unit	
Symbol	Item	Conditions	Conditions		Тур.	Max.	Unit	
I <sub>CES</sub>	Collector-emitter cut-off current	V <sub>CE</sub> =V <sub>CES</sub> , G-E short-circuited	-	-	1.0	mA		
I <sub>GES</sub>	Gate-emitter leakage current	V <sub>GE</sub> =V <sub>GES</sub> , C-E short-circuited	-	-	0.5	μA		
$V_{GE(th)}$	Gate-emitter threshold voltage	I <sub>C</sub> =40 mA, V <sub>CE</sub> =10 V		5.4	6.0	6.6	V	
.,		Ic=400 A, V <sub>GE</sub> =15 V,	T <sub>vj</sub> =25 °C	-	1.45	1.75		
V <sub>CEsat</sub> (Terminal)		Refer to the figure of test circuit	Refer to the figure of test circuit $T_{vj}$ =125 °C		1.55	-	V	
(Terminal)	Collector-emitter saturation voltage	(Note5)	T <sub>vj</sub> =150 °C	-	1.60	-		
.,	Collector-emitter saturation voltage	I <sub>C</sub> =400 A,	T <sub>vj</sub> =25 °C	-	1.30	1.55		
V <sub>CEsat</sub> (Chip)		V <sub>GE</sub> =15 V,	T <sub>vj</sub> =125 °C	-	1.35	-	V	
(Chip)		(Note5)	T <sub>vj</sub> =150 °C	-	1.35	-		
Cies	Input capacitance			-	-	53.5		
Coes	Output capacitance	V <sub>CE</sub> =10 V, G-E short-circuited		-	-	2.6	nF	
Cres	Reverse transfer capacitance		-	-	1.0			
Q <sub>G</sub>	Gate charge	V <sub>CC</sub> =300 V, I <sub>C</sub> =400 A, V <sub>GE</sub> =15 V	-	1.65	-	μC		
t <sub>d(on)</sub>	Turn-on delay time	V 200 V I 400 A V 45 V	-	-	400	ns		
tr	Rise time	V <sub>CC</sub> =300 V, I <sub>C</sub> =400 A, V <sub>GE</sub> =±15 V,	-	-	200			
t <sub>d(off)</sub>	Turn-off delay time	D 4.6.0 Industrial land	-	-	400			
t <sub>f</sub>	Fall time	R <sub>G</sub> =1.6 Ω, Inductive load	-	-	400			
A (Note 4)		I <sub>E</sub> =400 A, G-E short-circuited,	T <sub>vj</sub> =25 °C	-	2.10	2.90	V	
V <sub>EC</sub> (Note.1)		Refer to the figure of test circuit	T <sub>vj</sub> =125 °C	-	2.05	-		
(Terminal)		(Note5)	T <sub>vj</sub> =150 °C	-	2.05	-		
A (Note 4)	Emitter-collector voltage	I <sub>E</sub> =400 A,	T <sub>vj</sub> =25 °C	-	1.90	2.65		
V <sub>EC</sub> (Note.1) (Chip)		G-E short-circuited,	T <sub>vj</sub> =125 °C	-	1.80	-	V	
		(Note5)	T <sub>vj</sub> =150 °C	-	1.80	-	1	
t <sub>rr</sub> (Note1)	Reverse recovery time	V <sub>CC</sub> =300 V, I <sub>E</sub> =400 A, V <sub>GE</sub> =±15 V,		-	-	200	ns	
Q <sub>rr</sub> (Note1)	Reverse recovery charge	$R_G=1.6 \Omega$ , Inductive load	-	14	-	μC		
Eon	Turn-on switching energy per pulse	V <sub>CC</sub> =300 V, I <sub>C</sub> =I <sub>E</sub> =400 A,		-	4.5	-	1	
E <sub>off</sub>	Turn-off switching energy per pulse	$V_{GE}=\pm 15 \text{ V}, R_{G}=1.6 \Omega, T_{vj}=150 \text{ °C},$	-	21.6	-	mJ		
E <sub>rr</sub> (Note1)	Reverse recovery energy per pulse	Inductive load	-	9.0	-	mJ		
R <sub>CC'+EE'</sub>	Internal lead resistance	Main terminals-chip, per switch, T <sub>C</sub> =25	-	0.3	-	mΩ		
r <sub>g</sub>	Internal gate resistance	Per switch	-	1.5	-	Ω		

Publication Date : February 2017 CMH-11282 Ver.1.0

### HIGH POWER SWITCHING USE

### INSULATED TYPE

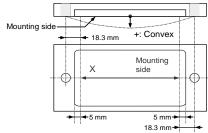
### THERMAL RESISTANCE CHARACTERISTICS

Symbol	Item	Conditions		Limits			Unit
				Min.	Тур.	Max.	Offic
$R_{th(j-c)Q}$	Thermal resistance	Junction to case, per Inverter IGBT (Note4)		-	-	53	K/kW
R <sub>th(j-c)D</sub>	Thermal resistance	Junction to case, per Inverter FWD (Note4)		=	-	84	
R <sub>th(c-s)</sub>	Contact thermal resistance	Case to heat sink,	Thermal grease applied (Note4, 6)	ı	24	1	K/kW
	Contact trieffial resistance	per 1 module,	PC-TIM applied (Note4, 7)	-	6.3	-	r/KVV

#### **MECHANICAL CHARACTERISTICS**

Symbol	ltom	Conditions		Limits			1.1:4
	Item			Min.	Тур.	Max.	Unit
M <sub>t</sub>	Mounting torque	Main terminals	M 5 screw	2.5	3.0	3.5	N∙m
Ms	Mounting torque	Mounting to heat sink	M 6 screw	3.5	4.0	4.5	N∙m
ds	Creepage distance	Terminal to terminal		18	-	-	
		Terminal to base plate		21.1	-	-	mm
da	Clearance	Terminal to terminal		9.6	-	-	
	Clearance	Terminal to base plate		16.7	-	-	mm
ec	Flatness of base plate	On the centerline (Note8)		±0	-	+200	μm
m	mass	-		-	155	-	g

- \*: This product is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU.
- Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free-wheeling diode (FWD).
  - 2. Junction temperature  $(T_{\nu j})$  should not increase beyond  $T_{\nu j\,m\,a\,x}$  rating.
  - 3. Pulse width and repetition rate should be such that the device junction temperature  $(T_{vj})$  dose not exceed  $T_{vjm\,ax}$  rating.
  - 4. Case temperature (T<sub>C</sub>) and heat sink temperature (T<sub>S</sub>) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.
  - 5. Pulse width and repetition rate should be such as to cause negligible temperature rise. Refer to the figure of test circuit.
  - 6. Typical value is measured by using thermally conductive grease of  $\lambda$ =0.9 W/(m·K)/D<sub>(C-S)</sub>=50  $\mu$ m.
  - 7. Typical value is measured by using PC-TIM of  $\lambda$ =3.4 W/(m·K)/D<sub>(C-S)</sub>=50  $\mu$ m.
  - 8. The base plate (mounting side) flatness measurement points (X) are shown in the following figure.



HIGH POWER SWITCHING USE

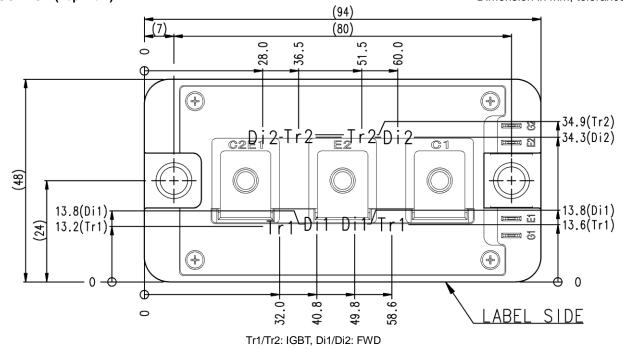
**INSULATED TYPE** 

### **RECOMMENDED OPERATING CONDITIONS**

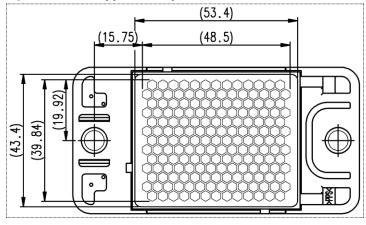
Symbol	Item	Conditions	Limits			Unit
		Conditions	Min.	Тур.	Max.	Uill
V <sub>cc</sub>	(DC) Supply voltage	Applied across C1-E2 terminals	-	300	450	V
$V_{GEon}$	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2 terminals	13.5	15.0	16.5	V
R <sub>G</sub>	External gate resistance	Per switch	1.6	-	16	Ω

### **CHIP LOCATION (Top view)**

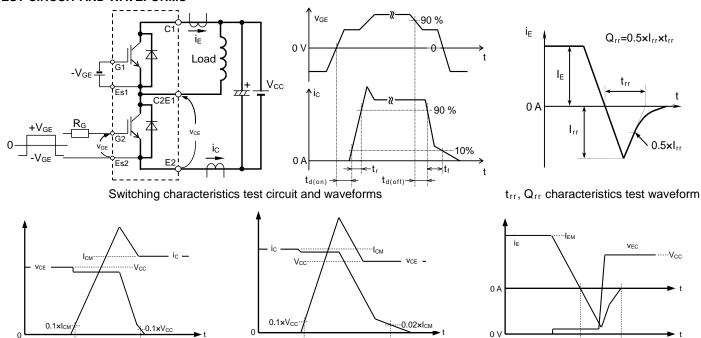
Dimension in mm, tolerance: ±1 mm



Option: PC-TIM applied baseplate outline

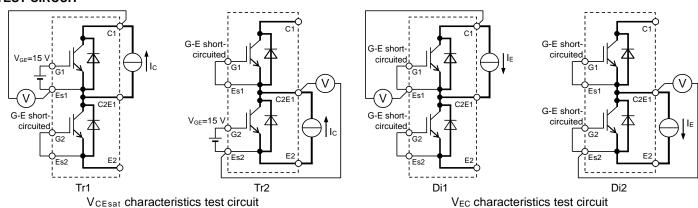


### **TEST CIRCUIT AND WAVEFORMS**



IGBT Turn-on switching energy IGBT Turn-off switching energy FWD Reverse recovery energy Turn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

### **TEST CIRCUIT**



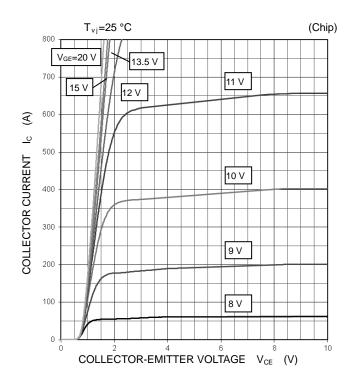
Publication Date : February 2017 CMH-11282 Ver.1.0

HIGH POWER SWITCHING USE

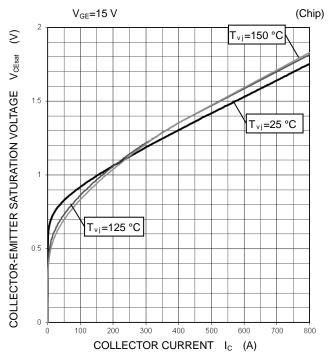
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### **PERFORMANCE CURVES**

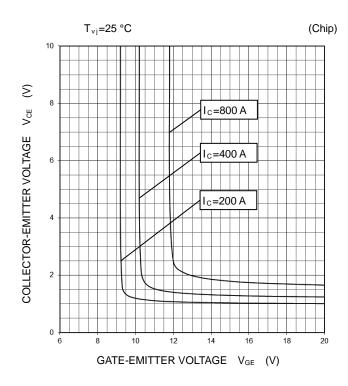
### OUTPUT CHARACTERISTICS (TYPICAL)



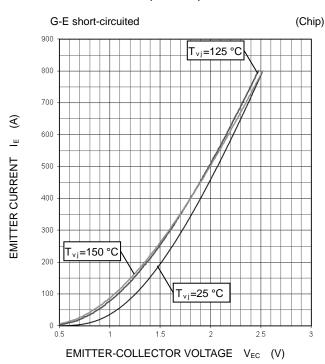
# COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)



# COLLECTOR-EMITTER VOLTAGE CHARACTERISTICS (TYPICAL)

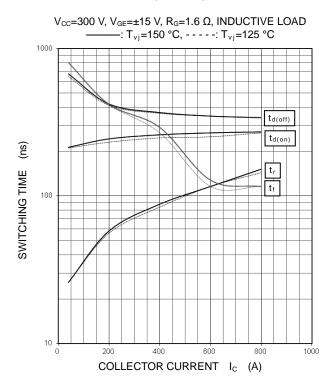


#### FREE WHEELING DIODE FORWARD CHARACTERISTICS (TYPICAL)

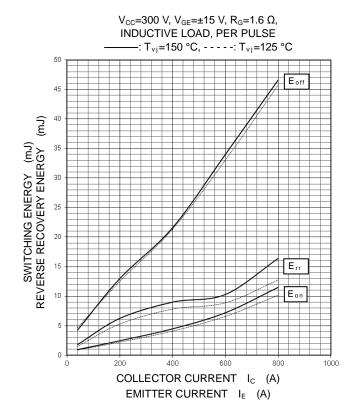


### **PERFORMANCE CURVES**

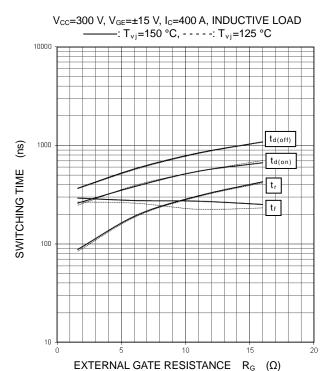
# HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



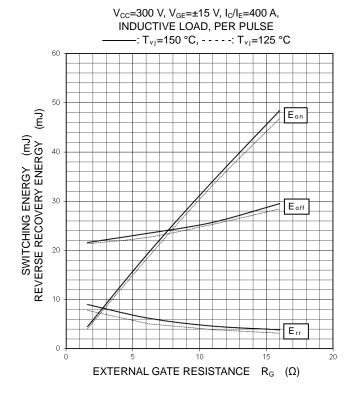
# HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



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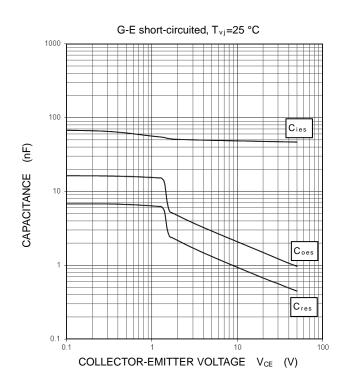


HIGH POWER SWITCHING USE

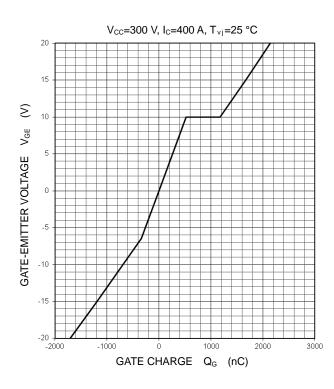
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### **PERFORMANCE CURVES**

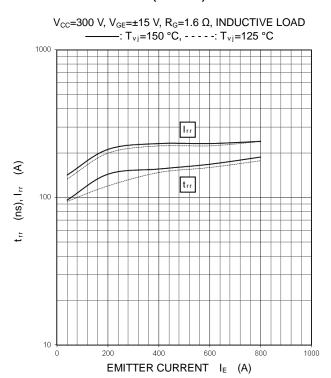
# CAPACITANCE CHARACTERISTICS (TYPICAL)



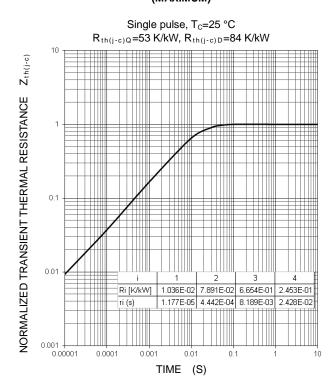
# GATE CHARGE CHARACTERISTICS (TYPICAL)



# FREE WHEELING DIODE REVERSE RECOVERY CHARACTERISTICS (TYPICAL)

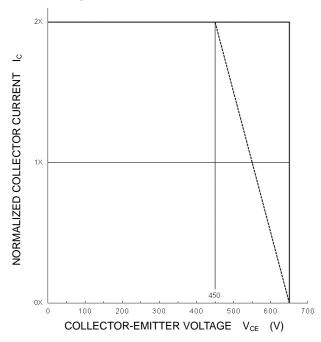


# TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS (MAXIMUM)



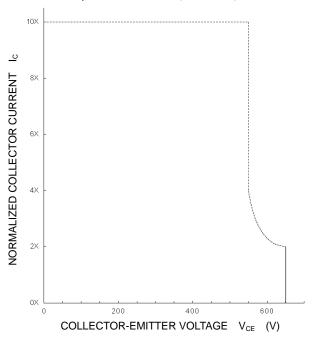
### **PERFORMANCE CURVES**

#### TURN-OFF SWITCHING SAFE OPERATING AREA (REVERSE BIAS SAFE OPERATING AREA) (MAXIMUM)



# SHORT-CIRCUIT SAFE OPERATING AREA (MAXIMUM)

$$\begin{split} &V_{CC}{\le}400~V,~V_{GE}{=}{\pm}15~V,~R_{G}{=}1.6{\sim}16~\Omega,\\ &T_{vj}{=}~25~{\sim}~150~^{\circ}C,~t_{W}{\le}8~\mu s,~Non-Repetitive \end{split}$$



Note: The characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

Publication Date : February 2017 CMH-11282 Ver.1.0 INSULATED TYPE

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